

Application/Control No. 10/520,760

Examiner Nathan Wiehe Applicant(s)/Patent under Reexamination
ASHIHARA ET AL.

Art Unit 3745

			ISSUE	CL	.AS	SIF	ICAT	ION					
	ORI	IGINAL	INTERNATIONAL CLASSIFICATION										
CLASS SUBCI			LASS CLAIMED							NON-CLAIME	NON-CLAIMED		
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Nathan Wiehe 11/21/06 (Assistant Examiner) (Date)					Qk RD K. I	LOOK	6	Total Claims Allowed: 3					
(Legal Instruments Examiner) (Date)					XE CEN	TER 3	37 000 e)		O.G. Print Fig				
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Claims renumbered in the same order as presented by applicant									□СРА			☐ T.D.			☐ R.1.47		
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6		36			66			96			126			156			186
7		37			67			97		1	127			157			187
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12		42]		72	1		102	0 (132			162			192
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